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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/829,583	CHEN ET AL.	
Examiner	Art Unit	
Leonardo Andújar	2826	

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Class	Subclass	Date	Examiner
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INT	ERFERENC	E SEARCHI	ED
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
257/690-799 (text serach only-see search history print out)	12/13/2005	LA